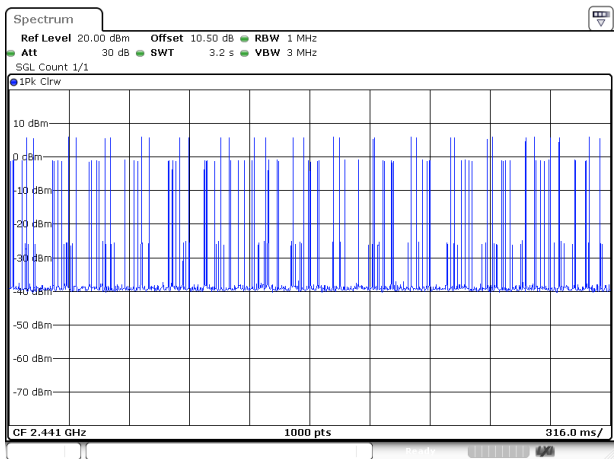
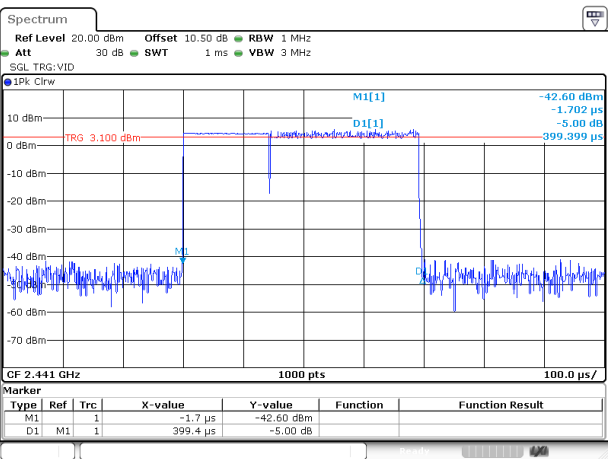


3DH1_Hopping



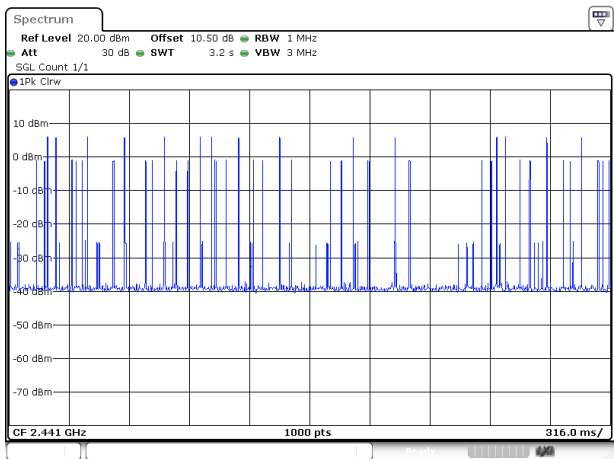
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:01:38

3DH1_Hopping



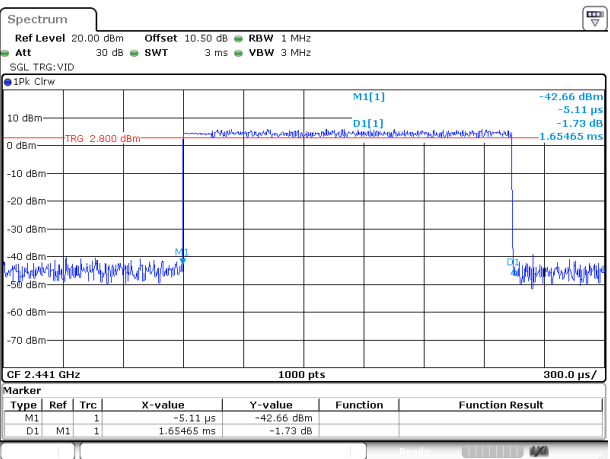
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:02:00

3DH3_Hopping



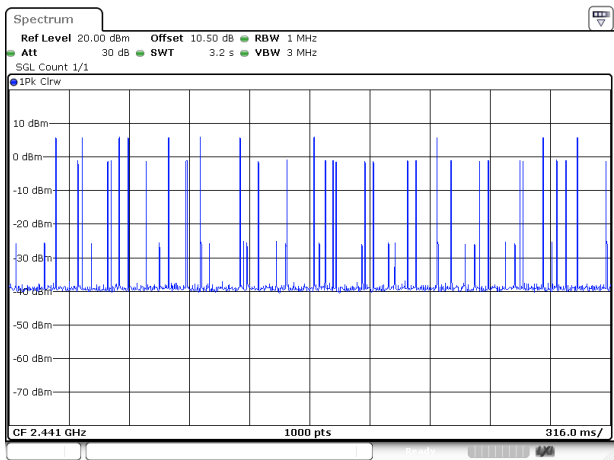
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:02:33

3DH3_Hopping



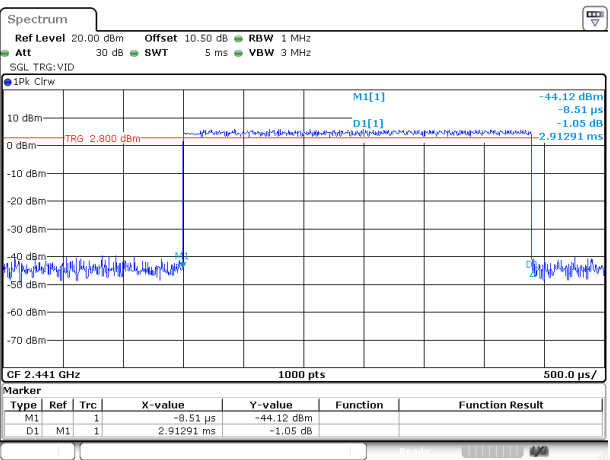
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:02:54

3DH5_Hopping



ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:03:09

3DH5_Hopping



ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 21:03:30

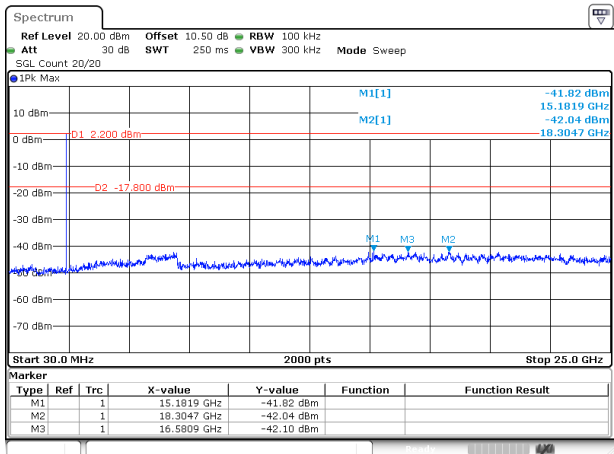
Conducted Spurious Emission**Test Information:**

Sample No.:	372D-3	Test Date:	2025/08/08
Test Site:	RF	Test Mode:	Transmitting
Tester:	Brian Li	Test Result:	Pass

Environmental Conditions:

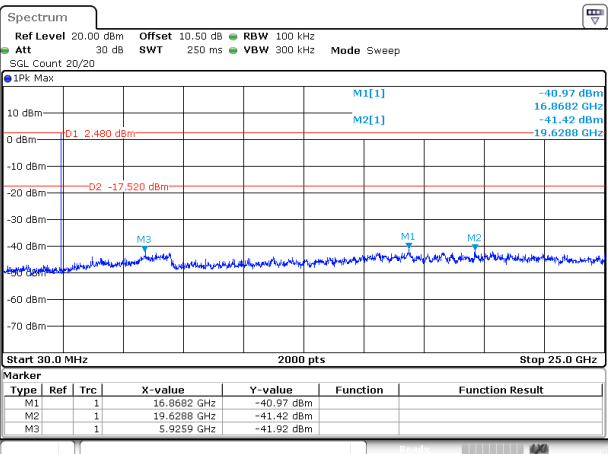
Temperature: (°C)	25	Relative Humidity: (%)	46	ATM Pressure: (kPa)	101
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DH1_Low



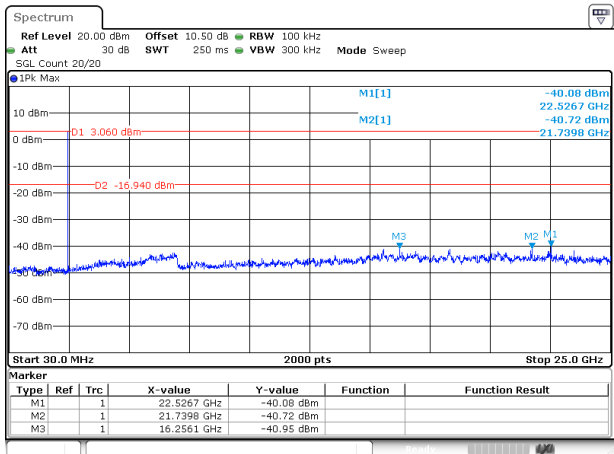
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 00:58:01

DH1_Middle



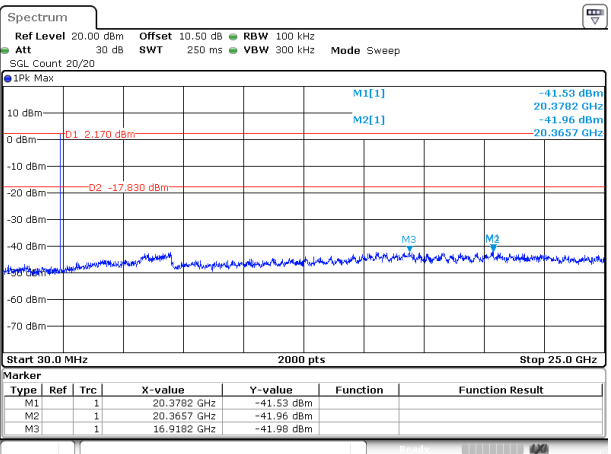
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 00:59:33

DH1_High



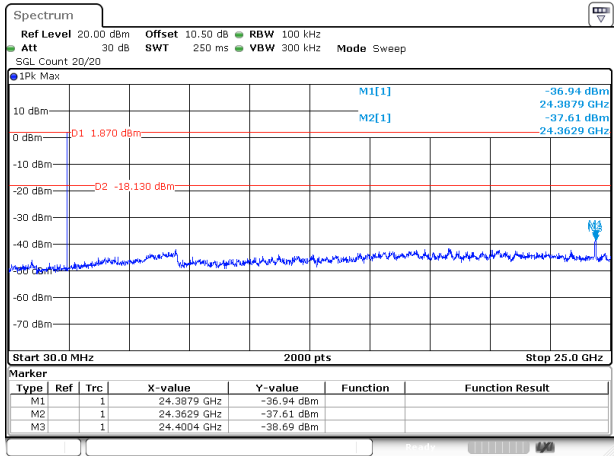
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 01:05:35

DH5_Low



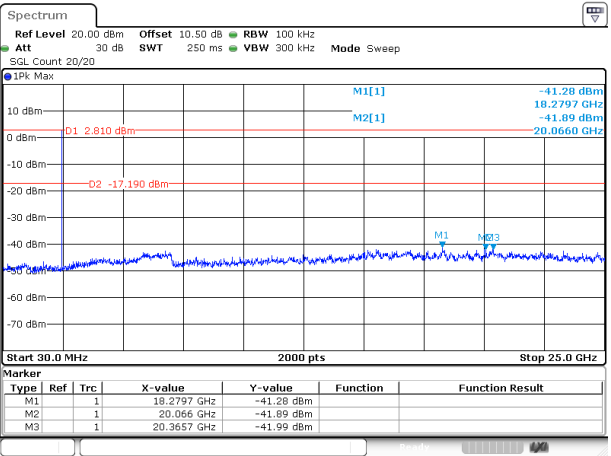
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 18:20:29

DH5_Middle



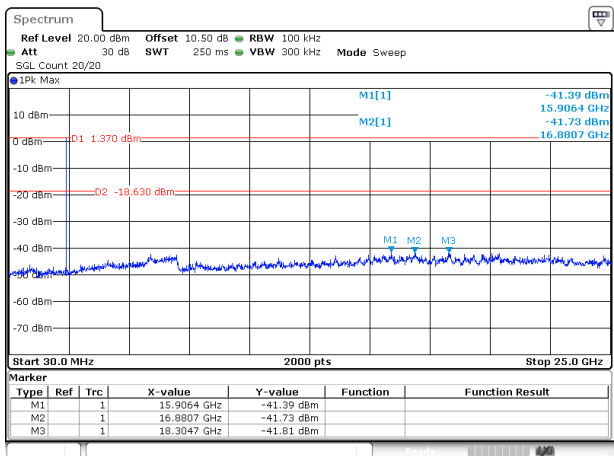
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 18:21:54

DH5_High



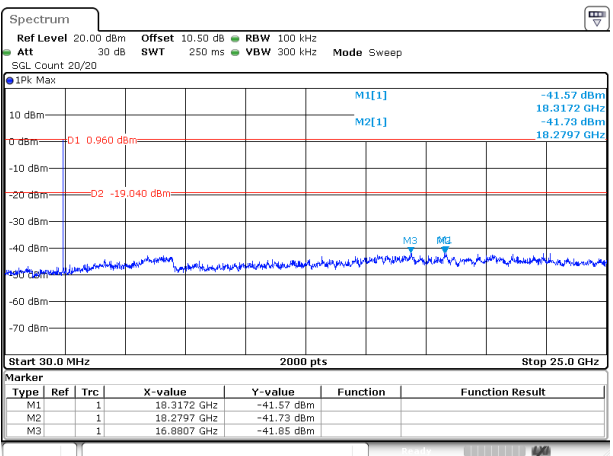
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 18:24:52

2DH1_Low



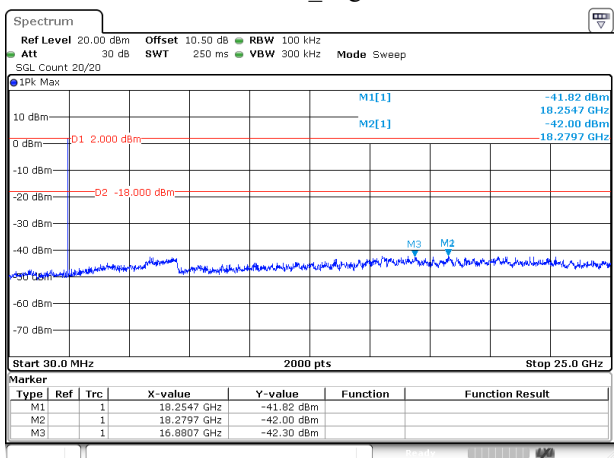
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:27:06

2DH1_Middle



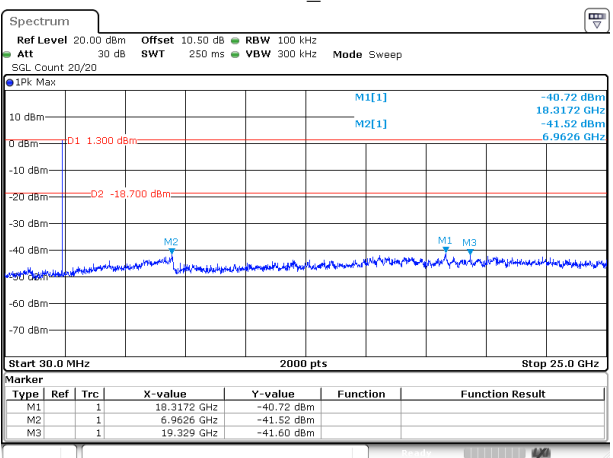
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:29:28

2DH1_High



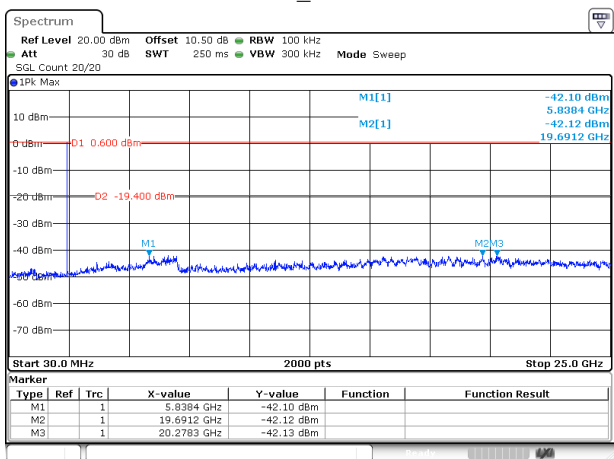
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:34:23

2DH5_Low



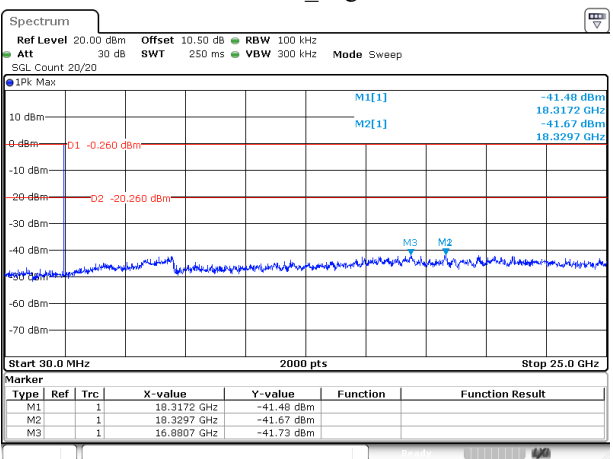
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:44:52

2DH5_Middle



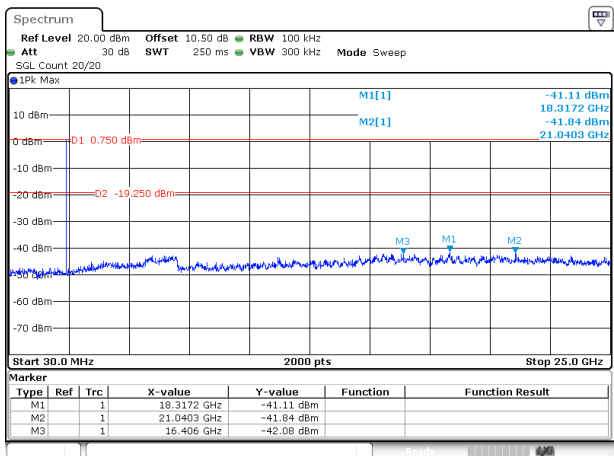
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:49:45

2DH5_High



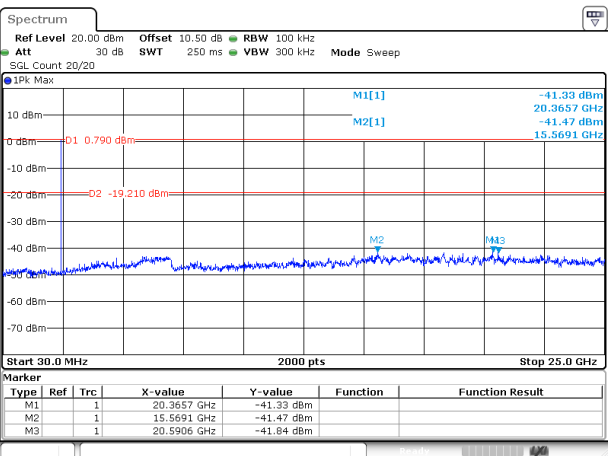
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:51:05

3DH1_Low



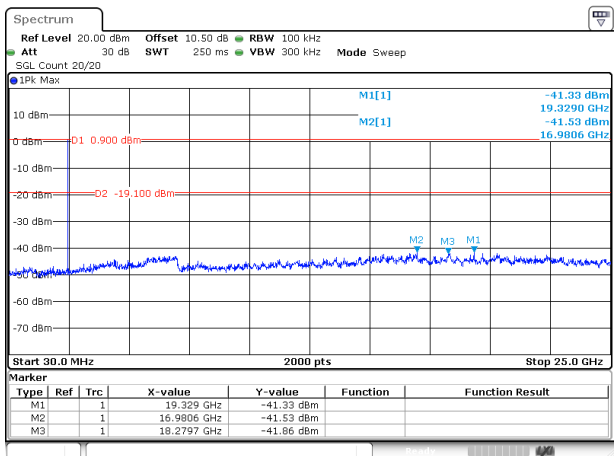
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:57:20

3DH1_Middle



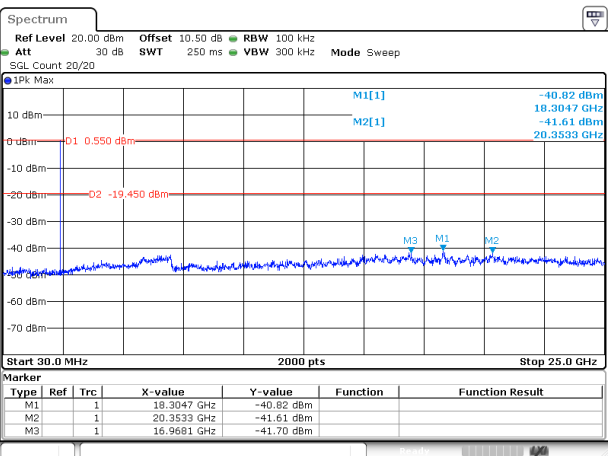
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 19:59:22

3DH1_High



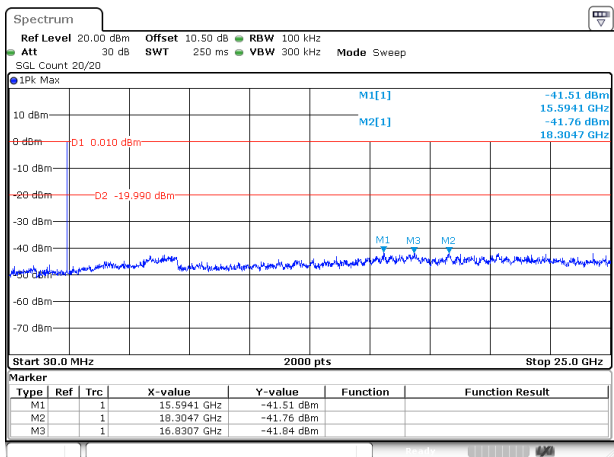
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 20:06:39

3DH5_Low



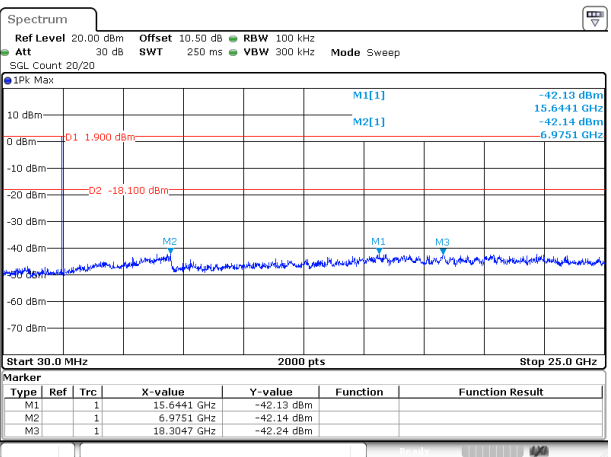
ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 20:13:18

3DH5_Middle



ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 20:15:05

3DH5_High



ProjectNo.:2501V12497E-RF Tester:Brian Li
Date: 8.AUG.2025 20:16:29

RF EXPOSURE EVALUATION

RF Exposure

Applicable Standard

FCC§1.1310, §2.1093 and RSS-102 Issue 6.

Test Result

Compliance, please refer to the SAR report: 2504V12497E-SAA, 2504V12497E-SAB.

EUT PHOTOGRAPHS

Please refer to the attachment 2501V12497E-RF-EXP External photo and 2501V12497E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501V12497E-RF-TSPB Test Setup photo.

******* END OF REPORT *******